

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- ☐ **BLACK BORDERS**
- ☐ **IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- ☐ **FADED TEXT OR DRAWING**
- ☐ **BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- ☐ **SKEWED/SLANTED IMAGES**
- ☐ **COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- ☐ **GRAY SCALE DOCUMENTS**
- ☐ **LINES OR MARKS ON ORIGINAL DOCUMENT**
- ☐ **REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- ☐ **OTHER:** _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	20123	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1 or reference\$1 or standard\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:35
S2	175	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1 or reference\$1 or standard\$1)) and (scatter\$3 near3 line\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:33
S3	5734	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:44
S4	38	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1)) and (scatter\$3 near3 line\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:34
S5	3041	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:46
S6	3449	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S7	126	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:41
S8	956	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:40

S9	40	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:56
S10	134765	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S11	3449	((((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:59
S12	3355	(((((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)) and (pixel\$1 or point\$1 or feature\$1 or characteristic\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:00
S13	3193	(((((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:00
S14	125	(((((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)) and (pixel\$1 or point\$1)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:01
S15	5751	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:26
S16	1977	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:24

S17	1411	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S18	1853	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S19	1356	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S20	749	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:30
S21	332	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:28
S22	184	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))) and (radiation or x-ray\$1 or xray\$1 or irradiation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:34

S23	57	(((((382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))) and (radiation or x-ray\$1 or xray\$1 or irradiation)) and (((similarit\$4 or feature\$1) near3 (table\$1 or list\$1 or value\$1)) or scor\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S24	4	"4851678".pn.",4962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S25	5807	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:27
S26	839	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S27	1140	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S28	468	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and ((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:31
S29	177	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and (((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6)) same (template\$1 or kernal\$1 or standard\$1 or pattern\$1 or mask\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:32

S30	246	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and (((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6)) same (template\$1 or kernal\$1 or standard\$1 or pattern\$1 or mask\$1 or reference\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:19
S31	4	"5343390".pn.",5962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/14 16:18
S32	8496	382/100,128,132,172,190,195,199,200,201,202,203,204,205,217,243,266.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:21
S33	303	S32 and (line\$1 or segment\$6 or edg\$5 or contour\$) and pixel\$1 and ((radiation or irradiation) near4 imag\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:24
S34	37	S33 and (irradiation near5 (field\$1 or area\$1 or section\$5 or segment\$4 or region\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:43
S35	94	S32 and (irradiation near5 (field\$1 or area\$1 or section\$5 or segment\$4 or region\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:43
S36	11	S35 and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:46
S37	615	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:47
S38	759	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7 or comb\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:48

S39	18	S38 and ((detect\$5 or recogniz\$6 or determin\$7) near6 (irradiation near4 (section\$ or lin\$3 or area\$ or region\$4 or segment\$5 or field\$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:51
-----	----	--	---	----	-----	------------------

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



>> See

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **15** of **1097671** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Evaluation of a structured cesium iodide film for radiation imaging purposes
Jing, T.; Goodman, C.A.; Cho, G.; Drewery, J.; Hong, W.S.; Lee, H.; Kaplan, I.; Miresghhi, A.; Perez-Mendez, V.; Wildermuth, D.;

Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IEEE Conference Record. , 31 Oct.-6 Nov. 1993

Pages:1878 - 1882 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) IEEE CNF

2 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection
Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagou, M.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.; Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trim, M.; Ulrici, J.; Treis, J.;

Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 3 , June 2004

Pages:1121 - 1128

[\[Abstract\]](#) [\[PDF Full-Text \(616 KB\)\]](#) IEEE JNL

3 An asynchronous pixel architecture for simultaneous radiation imaging and spectroscopy on a real-time basis
Kapnistis, C.; Misiakos, K.; Haralabidis, N.; Kyriakis-Bitaros, D.;

Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002

Pages:1802 - 1807

[\[Abstract\]](#) [\[PDF Full-Text \(244 KB\)\]](#) IEEE JNL

4 A novel radiation imaging sensor based on self-activated pixels

Kavadias, S.; Misiakos, K.; Loukas, D.;
Nuclear Science, IEEE Transactions on , Volume: 42 , Issue: 3 , June 1995
Pages:155 - 162

[[Abstract](#)] [[PDF Full-Text \(636 KB\)](#)] **IEEE JNL**

5 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection

Wermes, N.; Andricek, L.; Fischer, P.; Harter, M.; Herrmann, S.; Karagounis, Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, R.; Soltan, H.; Struder, L.; Trimpl, M.; Ulrici, J.; Treis, J.;
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19-20 Oct. 2003
Pages:325 - 330 Vol.1

[[Abstract](#)] [[PDF Full-Text \(722 KB\)](#)] **IEEE CNF**

6 Radiation imaging with 2D a-Si sensor arrays

Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;
Nuclear Science Symposium and Medical Imaging Conference, 1991., Conference Record of the 1991 IEEE , 2-9 Nov. 1991
Pages:1882 - 1886 vol.3

[[Abstract](#)] [[PDF Full-Text \(404 KB\)](#)] **IEEE CNF**

7 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip

Conti, M.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;
Nuclear Science, IEEE Transactions on , Volume: 50 , Issue: 4 , Aug. 2003
Pages:869 - 877

[[Abstract](#)] [[PDF Full-Text \(1541 KB\)](#)] **IEEE JNL**

8 Radiation imaging with 2D a-Si sensor arrays

Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;
Nuclear Science, IEEE Transactions on , Volume: 39 , Issue: 4 , Aug 1992
Pages:1056 - 1062

[[Abstract](#)] [[PDF Full-Text \(668 KB\)](#)] **IEEE JNL**

9 Report from the 5th International Workshop on Radiation Imaging Detectors

Ludwig, J.;
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19-20 Oct. 2003
Pages:117 - 119 Vol.1

[[Abstract](#)] [[PDF Full-Text \(1118 KB\)](#)] **IEEE CNF**

10 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip

Maionino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;
Nuclear Science Symposium Conference Record, 2002 IEEE , Volume: 1 , 10-11 Oct. 2002

Nov. 2002
Pages:189 - 193 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(895 KB\)\]](#) [IEEE CNF](#)

11 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science Symposium and Medical Imaging Conference Record, 1995.,
IEEE , Volume: 1 , 21-28 Oct. 1995

Pages:18 - 22 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) [IEEE CNF](#)

12 Portable system for imaging of /spl alpha/, and X-ray sources with silicon pixel detectors and Medipix1 readout

Bertolucci, E.; Boerkamp, T.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russo

Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002

Pages:1845 - 1850

[\[Abstract\]](#) [\[PDF Full-Text \(573 KB\)\]](#) [IEEE JNL](#)

13 Analysis of images of radiation due to plasma-limiter interaction

Peterson, B.J.; Ashikawa, N.; Kostrioukov, A.Yu.; Nishimura, K.; Kojima, H.; S. S.;

Plasma Science, IEEE Transactions on , Volume: 30 , Issue: 1 , Feb. 2002

Pages:52 - 53

[\[Abstract\]](#) [\[PDF Full-Text \(278 KB\)\]](#) [IEEE JNL](#)

14 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science, IEEE Transactions on , Volume: 43 , Issue: 3 , June 1996

Pages:1102 - 1106

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) [IEEE JNL](#)

15 Robust window discriminator for photon-counting pixel detectors

Oelmann, B.; Abdalla, M.; O'Nils, M.;

Optoelectronics, IEE Proceedings- , Volume: 149 , Issue: 2 , April 2002

Pages:65 - 69

[\[Abstract\]](#) [\[PDF Full-Text \(371 KB\)\]](#) [IEEE JNL](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) |
[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

>> Se

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **11** of **1097671** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

radiation images<and>lines

Search

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Optical transition radiation imaging of intense proton beams at FNA
Scarpine, V.E.; Lumpkin, A.H.; Schappert, W.; Tassotto, G.R.;
 Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 4 , Aug. 2004
 Pages:1529 - 1532

[\[Abstract\]](#) [\[PDF Full-Text \(296 KB\)\]](#) IEEE JNL

2 Terahertz radiation imaging of vortices penetrated into YBCO thin film
Tonouchi, M.; Moto, A.; Yamashita, M.; Hangyo, M.;
 Applied Superconductivity, IEEE Transactions on , Volume: 11 , Issue: 1 , Mar 2001
 Pages:3230 - 3233

[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) IEEE JNL

3 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption
Misiakos, K.; Kavadias, S.;
 Nuclear Science Symposium and Medical Imaging Conference Record, 1995., IEEE , Volume: 1 , 21-28 Oct. 1995
 Pages:18 - 22 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) IEEE CNF

4 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection
Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagou, M.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.; Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trim, M.; Ulrici, J.; Treis, J.;

Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 3 , June 2004
Pages:1121 - 1128

[\[Abstract\]](#) [\[PDF Full-Text \(616 KB\)\]](#) **IEEE JNL**

5 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science, IEEE Transactions on , Volume: 43 , Issue: 3 , June 1996
Pages:1102 - 1106

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) **IEEE JNL**

6 A novel radiation imaging sensor based on self-activated pixels

Kavadias, S.; Misiakos, K.; Loukas, D.;

Nuclear Science, IEEE Transactions on , Volume: 42 , Issue: 3 , June 1995
Pages:155 - 162

[\[Abstract\]](#) [\[PDF Full-Text \(636 KB\)\]](#) **IEEE JNL**

7 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection

Wermes, N.; Andricek, L.; Fischer, P.; Harter, M.; Herrmann, S.; Karagounis, Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, R.; Soltau, H.; Struder, L.; Trimpl, M.; Ulrici, J.; Treis, J.;

Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19-20 Oct. 2003
Pages:325 - 330 Vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(722 KB\)\]](#) **IEEE CNF**

8 The feasibility of OTR imaging of high-intensity proton beams at FN/

Lumpkin, A.H.; Scarpine, V.;

Particle Accelerator Conference, 2003. PAC 2003. Proceedings of the , Volume 4 , 12-16 May 2003
Pages:2414 - 2416 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(1351 KB\)\]](#) **IEEE CNF**

9 A high resolution ultrasonic imaging system for the detection of cervical cancer

van der Heiden, M.; Faber, G.; Ongkiehong, L.; Berkhout, A.J.;

Ultrasonics Symposium, 1996. Proceedings., 1996 IEEE , Volume: 2 , 3-6 Nov 1996
Pages:1341 - 1344 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(528 KB\)\]](#) **IEEE CNF**

10 Effect of multi-layers of image planes on PCB radiation

Jinsuk Kim; Kilnam Oh;

Electromagnetic Compatibility, 1996. Symposium Record. IEEE 1996 International Symposium on , 19-23 Aug. 1996
Pages:322 - 325

[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) IEEE CNF

11 Evaluation of a structured cesium iodide film for radiation imaging purposes

Jing, T.; Goodman, C.A.; Cho, G.; Drewery, J.; Hong, W.S.; Lee, H.; Kaplan, : Mireshghi, A.; Perez-Mendez, V.; Wildermuth, D.;

Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IE Conference Record. , 31 Oct.-6 Nov. 1993

Pages:1878 - 1882 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) IEEE CNF

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

» Se.

Help / FAQ Terms IEEE Peer Review

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **2** of **1097671** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

radiation images<and>edges

Search

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 An adaptive smoothing filter for URTURIP images

Migeon, B.; Serfaty, V.; Gorkani, M.; Marche, P.;

Engineering in Medicine and Biology Magazine, IEEE, Volume: 14, Issue: 6, Dec. 1995

Pages:762 - 765

[\[Abstract\]](#) [\[PDF Full-Text \(452 KB\)\]](#) IEEE JNL

2 A contour association method for the 3D reconstruction of long bone obtained with the URTURIP technique

Migeon, B.; Deforge, P.; Marche, P.;

Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the IEEE, Volume: 2, 29 Oct.-1 Nov. 1998

Pages:588 - 589 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(176 KB\)\]](#) IEEE CNF

Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
 New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
 Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)Welcome
United States Patent and Trademark Office

» Se

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1097671** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

» Se

Help FAQ Terms IEEE Peer Review

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **6** of **1097671** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

radiation images<and>segments

Search

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 An adaptive smoothing filter for URTURIP images

Migeon, B.; Serfaty, V.; Gorkani, M.; Marche, P.;

Engineering in Medicine and Biology Magazine, IEEE, Volume: 14, Issue: 6, Dec. 1995

Pages:762 - 765

[\[Abstract\]](#)[\[PDF Full-Text \(452 KB\)\]](#)

IEEE JNL

2 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science Symposium and Medical Imaging Conference Record, 1995., IEEE, Volume: 1, 21-28 Oct. 1995

Pages:18 - 22 vol.1

[\[Abstract\]](#)[\[PDF Full-Text \(388 KB\)\]](#)

IEEE CNF

3 Development of an orthogonal-stripe CdZnTe gamma radiation imaging spectrometer

Macri, J.R.; Apotovsky, B.A.; Butler, J.F.; Cherry, M.L.; Dann, B.K.; Drake, A.; Doty, F.P.; Guzik, T.G.; Larson, K.; Mayer, M.; McConnell, M.L.; Ryan, J.M.;

Nuclear Science, IEEE Transactions on, Volume: 43, Issue: 3, June 1996

Pages:1458 - 1462

[\[Abstract\]](#)[\[PDF Full-Text \(348 KB\)\]](#)

IEEE JNL

4 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science, IEEE Transactions on, Volume: 43, Issue: 3, June 1996

Pages:1102 - 1106

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) **IEEE JNL**

5 A contour association method for the 3D reconstruction of long bones obtained with the URTURIP technique

Migeon, B.; Deforge, P.; Marche, P.;

Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the IEEE , Volume: 2 , 29 Oct.-1 Nov. 1998

Pages:588 - 589 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(176 KB\)\]](#) **IEEE CNF**

6 Development of an orthogonal-stripe CdZnTe gamma radiation imaging spectrometer

Macri, J.R.; Apotovsky, B.A.; Butler, J.F.; Cherry, M.L.; Dann, B.K.; Drake, A.; Doty, F.P.; Guzik, T.G.; Larson, K.; Mayer, M.; McConnell, M.L.; Ryan, J.M.;

Nuclear Science Symposium and Medical Imaging Conference Record, 1995., IEEE , Volume: 1 , 21-28 Oct. 1995

Pages:174 - 178 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(340 KB\)\]](#) **IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

» Search

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **1** of **1097671** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

radiation images<and>contours

Search

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 A contour association method for the 3D reconstruction of long bone obtained with the URTURIP technique***Migeon, B.; Deforge, P.; Marche, P.;*

Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the IEEE, Volume: 2, 29 Oct.-1 Nov. 1998

Pages:588 - 589 vol.2

[\[Abstract\]](#)[\[PDF Full-Text \(176 KB\)\]](#)**IEEE CNF**

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved